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October 2008

FDS4897AC

Dual N & P-Channel PowerTrench® MOSFET

N-Channel: 40 V, 6.1 A, 26 m Ω P-Channel: -40 V, -5.2 A, 39 m Ω

Features

Q1: N-Channel

- Max $r_{DS(on)}$ = 26 m Ω at V_{GS} = 10 V, I_D = 6.1 A
- Max $r_{DS(on)} = 31 \text{ m}\Omega$ at $V_{GS} = 4.5 \text{ V}$, $I_D = 5.6 \text{ A}$

Q2: P-Channel

- Max $r_{DS(on)}$ = 39 m Ω at V_{GS} = -10 V, I_D = -5.2 A
- Max $r_{DS(on)}$ = 65 m Ω at V_{GS} = -4.5 V, I_D = -4.1 A
- 100% UIL Tested
- RoHS Compliant

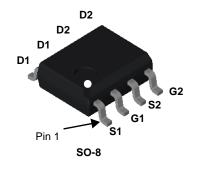


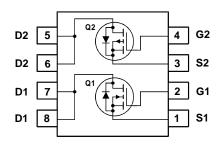
General Description

These dual N- and P-Channel MOSFETs are produced using Fairchild Semiconductor's advanced PowerTrench® process that has been especially tailored to minimize on-state resistance and yet maintain superior switching performance.

Applications

- Inverter
- Power Supplies





MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Parameter			Q1	Q2	Units
V_{DS}	Drain to Source Voltage			40	-40	V
V_{GS}	Gate to Source Voltage			±20	±20	V
	Drain Current - Continuous		6.1	-5.2	۸	
I _D	- Pulsed			24	-24	A
	Power Dissipation for Dual Operation			2	.0	
P_{D}	Power Dissipation for Single Operation	T _A = 25 °C	(Note 1a)	e 1a) 1.6		W
		T _A = 25 °C	(Note 1b)	0	.9	
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	37	73	mJ
T _J , T _{STG}	Operating and Storage Junction Temperature Range -55 to +150				°C	

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case,	(Note 1)	40	°C/M
$R_{\theta JC}$	Thermal Resistance, Junction to Ambient,	(Note 1a)	78	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDS4897AC	FDS4897AC	SO-8	13 "	12 mm	2500 units

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Type	Min	Тур	Max	Units
Off Chara	acteristics						
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$ $I_D = -250 \mu A, V_{GS} = 0 V$	Q1 Q2	40 -40			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μA, referenced to 25 °C I_D = -250 μA, referenced to 25 °C	Q1 Q2		37 -32		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 32 V, V _{GS} = 0 V V _{DS} = -32 V, V _{GS} = 0 V	Q1 Q2			1 -1	μА
I _{GSS}	Gate to Source Leakage Current	V _{GS} = ±20 V, V _{DS} = 0 V	Q1 Q2			±100 ±100	nA nA

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 250 \mu A$	Q1	1.5	2.0	3.0	V
- GS(III)		$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	Q2	-1.5	-2.0	-3.0	-
$\Delta V_{GS(th)}$	Gate to Source Threshold Voltage	$I_D = 250 \mu A$, referenced to 25 °C	Q1		-6		mV/°C
ΔT_{J}	Temperature Coefficient	I_D = -250 μ A, referenced to 25 °C	Q2		6		IIIV/ C
	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 6.1 \text{ A}$			20	26	
		$V_{GS} = 4.5 \text{ V}, I_D = 5.6 \text{ A}$	Q1		24	31	
-		$V_{GS} = 10 \text{ V}, I_D = 6.1 \text{ A}, T_J = 125 ^{\circ}\text{C}$			30	39	mΩ
r _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = -10 \text{ V}, I_D = -5.2 \text{ A}$			28	39	11122
		$V_{GS} = -4.5 \text{ V}, I_{D} = -4.1 \text{ A}$	Q2		45	65	
		$V_{GS} = -10 \text{ V}, I_D = -5.2 \text{ A}, T_J = 125 \text{ °C}$			41	57	
a	Forward Transconductance	$V_{DD} = 5 \text{ V}, I_D = 6.1 \text{ A}$	Q1		24		S
9 _{FS}	Forward Transconductance	$V_{DD} = -5 \text{ V}, \ I_{D} = -5.2 \text{ A}$	Q2		14		3

Dynamic Characteristics

C _{iss}	Input Capacitance	Q1 V _{DS} = 20 V, V _{GS} = 0 V, f = 1 MHZ	Q1 Q2	795 765	1055 1015	pF
C _{oss}	Output Capacitance	Q2	Q1 Q2	95 135	130 180	pF
C _{rss}	Reverse Transfer Capacitance	$V_{DS} = -20 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHZ}$	Q1 Q2	65 80	100 120	pF
R_g	Gate Resistance		Q1 Q2	1.7 3.6		Ω

Switching Characteristics

t _{d(on)}	Turn-On Delay Time	Q1	Q1 Q2	6 8	12 15	ns
t _r	Rise Time	$V_{DD} = 20 \text{ V, } I_{D} = 6.1 \text{ A,}$ $V_{GS} = 10 \text{ V, } R_{GEN} = 6 \Omega$	Q1 Q2	2 3	10 10	ns
t _{d(off)}	Turn-Off Delay Time	Q2 V _{DD} = -20 V, I _D = -5.2 A,	Q1 Q2	17 17	30 30	ns
t _f	Fall Time	$V_{GS} = -10 \text{ V}, R_{GEN} = 6 \Omega$	Q1 Q2	2	10 10	ns
Q _{g(TOT)}	Total Gate Charge	Q1	Q1 Q2	15 15	21 20	nC
Q _{gs}	Gate to Source Charge	$V_{GS} = 10 \text{ V}, V_{DD} = 20 \text{ V}, I_D = 6.1 \text{ A}$	Q1 Q2	2.5 2.6		nC
Q _{gd}	Gate to Drain "Miller" Charge	$V_{GS} = -10 \text{ V}, V_{DD} = -20 \text{ V}, I_D = -5.2 \text{ A}$	Q1 Q2	2.9 3.2		nC

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

Parameter

Drain-	rain-Source Diode Characteristics							
V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 1.3 \text{ A}$ $V_{GS} = 0 \text{ V}, I_S = -1.3 \text{ A}$	(Note 2) (Note 2)	Q1 Q2		0.75 -0.76	1.2 -1.2	V
		V _{GS} = 0 V, I _S = -1.3 A	(Note 2)	Q2 Q1		17	31	
t _{rr}	Reverse Recovery Time	I _F = 6.1 A, di/dt = 100 A/s		Q2		20	36	ns
Q _{rr}	Reverse Recovery Charge	Q2	=	Q1		7	15	nC
∝ rr	Trovorso resourcity charge	$I_F = -5.2 \text{ A}, \text{ di/dt} = 100 \text{ A/s}$		Q2		10	20	

Test Conditions

Notes:

Symbol

1: R_{UJA} is determined with the device mounted on a 1in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{BJC} is guaranteed by design while R_{BCA} is determined by the user's board design.



a) 78 °C/W when mounted on a 1 in² pad of 2 oz copper



b) 135 °C/W when mounted on a minimun pad

Type

Min

Тур

Max

Units

- 2: Pulse Test: Pulse Width < $300~\mu s$, Duty cycle < 2.0%. 3: Starting $T_J = 25~^{\circ}C$, N-ch: L = 3~mH, $I_{AS} = 5~A$, $V_{DD} = 40~V$, $V_{GS} = 10~V$; P-ch: L = 3~mH, $I_{AS} = -7~A$, $V_{DD} = -40~V$, $V_{GS} = -10~V$.

Typical Characteristics (Q1 N-Channel) T_J = 25 °C unless otherwise noted

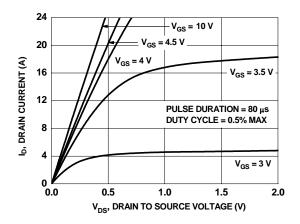


Figure 1. On Region Characteristics

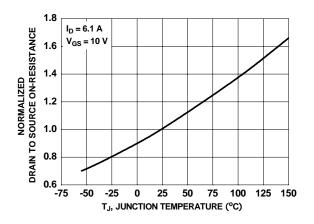


Figure 3. Normalized On Resistance vs Junction Temperature

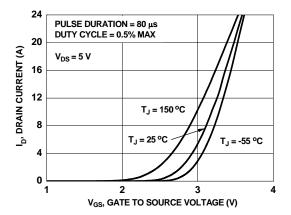


Figure 5. Transfer Characteristics

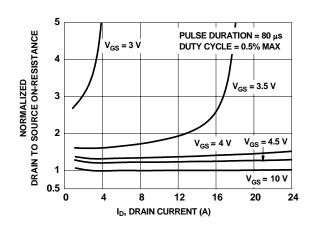


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

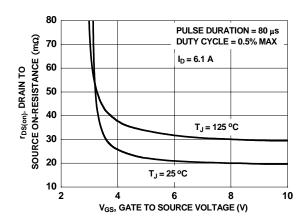


Figure 4. On-Resistance vs Gate to Source Voltage

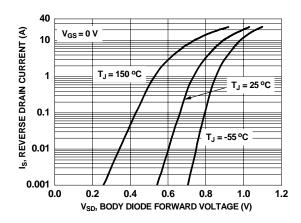


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics (Q1 N-Channel) T_J = 25 °C unless otherwise noted

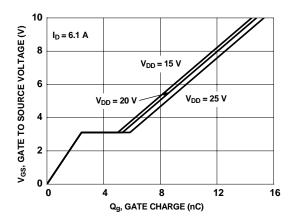


Figure 7. Gate Charge Characteristics

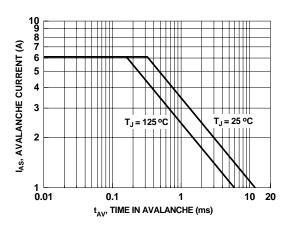


Figure 9. Unclamped Inductive Switching Capability

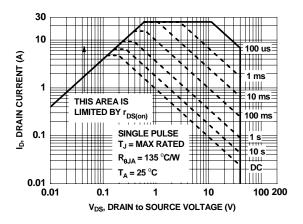


Figure 11. Forward Bias Safe Operating Area

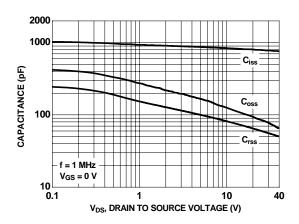


Figure 8. Capacitance vs Drain to Source Voltage

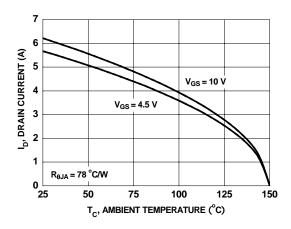


Figure 10. Maximum Continuous Drain Current vs Ambient Temperature

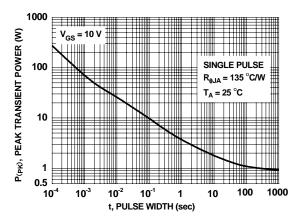


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics (Q1 N-Channel) T_J = 25 °C unless otherwise noted

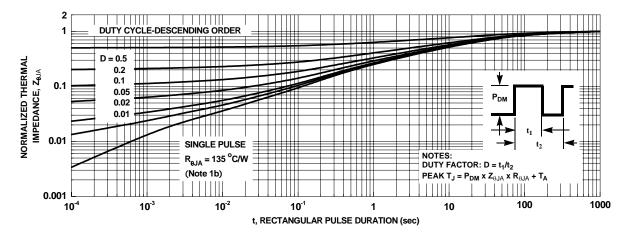


Figure 13. Junction-to-Ambient Transient Thermal Response Curve

Typical Characteristics (Q2 P-Channel) T_J = 25 °C unless otherwise noted

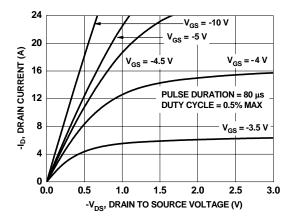


Figure 15. On- Region Characteristics

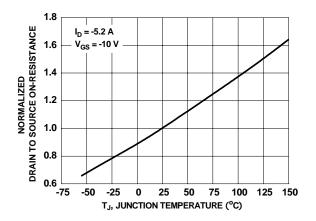


Figure 17. Normalized On-Resistance vs Junction Temperature

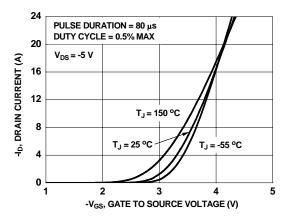


Figure 19. Transfer Characteristics

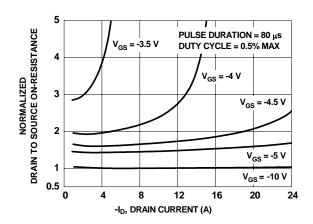


Figure 16. Normalized on-Resistance vs Drain Current and Gate Voltage

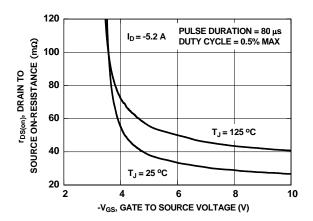


Figure 18. On-Resistance vs Gate to Source Voltage

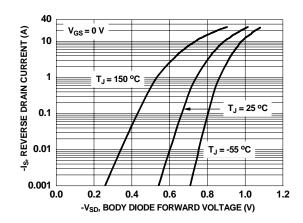


Figure 20. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics (Q2 P-Channel) T_J = 25 °C unless otherwise noted

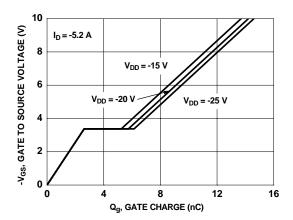


Figure 21. Gate Charge Characteristics

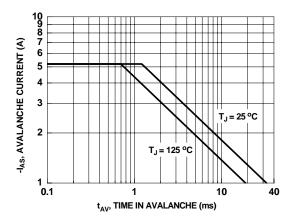


Figure 23. Unclamped Inductive Switching Capability

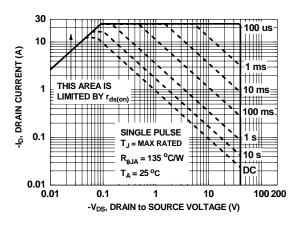


Figure 25. Forward Bias Safe Operating Area

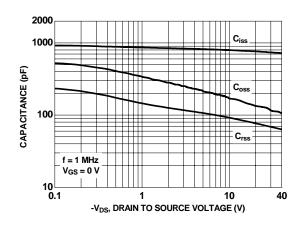


Figure 22. Capacitance vs Drain to Source Voltage

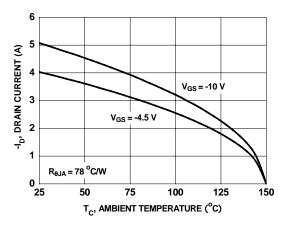


Figure 24. Maximum Continuous Drain Current vs Ambient Temperature

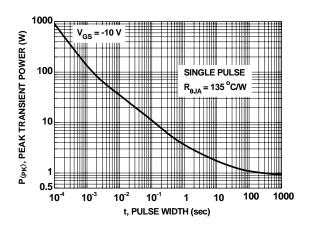


Figure 26. Single Pulse Maximum Power Dissipation

Typical Characteristics (Q2 P-Channel) T_J = 25 °C unless otherwise noted

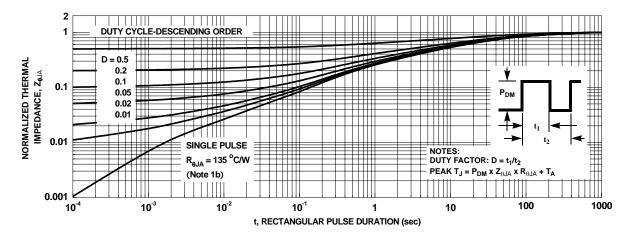


Figure 27. Junction-to-Ambient Transient Thermal Response Curve





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